

Notice of References Cited	Application/Control No. 10/767,046	Applicant(s)/Patent Under Reexamination BURDINE, TODD MICHAEL	
	Examiner Phung My Chung	Art Unit 2138	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0131294 A1	07-2003	Motika et al.	714/718
	B	US-			
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"A Technique for Fault Diagnosis of Defects in Scan Chains" by Guo et al, IEEE, paper 10.2, pgs. 268-277. 2001
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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